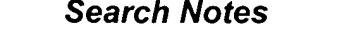


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/815,162	WU, STEPHEN	
	Examiner Hiep Nguyen	Art Unit 2816	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner